



IEEE SW Test Workshop

Semiconductor Wafer Test Workshop

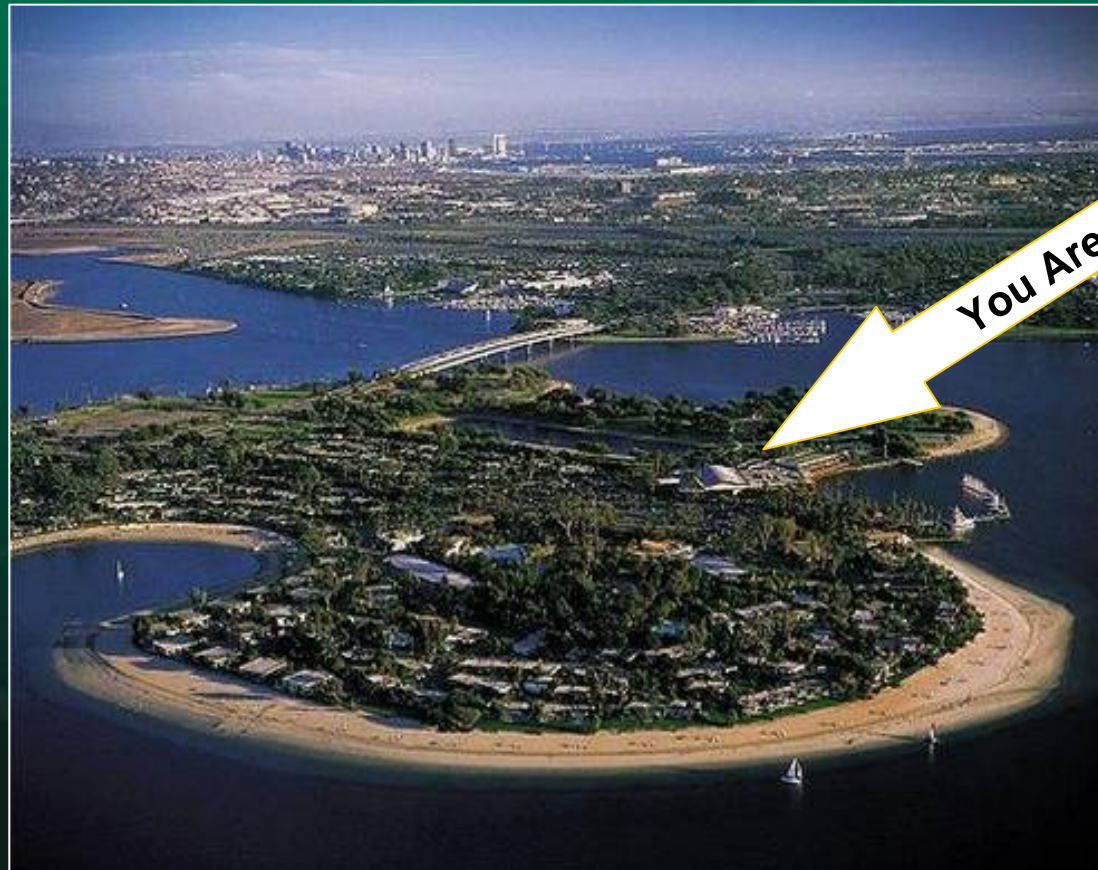
Welcome to the IEEE SW Test Workshop

Jerry Broz, Ph.D.
SW Test General Chair

June 7 to 10, 2009
San Diego, CA USA



19th Annual SWTW 2009



Paradise Point and Spa, San Diego, CA



June 7 to 10, 2009

IEEE SW Test Workshop

IEEE SW-Test Workshop

- **SW Test IS a Probe Technology Forum ...**
 - It is **“THE”** Conference for Wafer Test Professionals
 - Practical solutions to real problems
 - A balance mixture of semiconductor manufacturer and supplier presentations
- **Informal Conference ...**
 - Great social activities and informal discussions
 - Meet new people and have a little fun !



IEEE SW-Test Workshop

- **Sponsored by the IEEE Components, Packaging and Manufacturing Technology (CPMT) Society**
- **Leading international forum for scientists and engineers engaged in the research, design and development of revolutionary advances in micro-systems packaging and manufacture.**



What's New for 2009 ?

- **Technical Program**
 - 9 Technical Sessions with 31 Podium Presentations
- **Products / Services EXPO – 2009**
 - 28 full size booths
- **Corporate Support Program**
 - Five corporate supporters ... THANKS !
- **Major Website Redesign and Facelift**
- **New Committee Members**
 - Darren James, Rudolph Technologies
 - Roger Hayward, Cascade Microtech
 - Jan Martens, NXP Semiconductor
 - Rod Martens, FormFactor, Inc.
 - Frank Pietzschmann, Qimonda AG



SWTW Website Redesign

- You talked ... and we listened.
- New Look for Easier Navigation
- Central Repository
 - Past presentations
 - Online registration
 - Current news for SW Test Workshop
 - Mailing list sign-up
- Tremendous on-line resource !!

The screenshot shows the IEEE SW Test Workshop website. At the top, the logo features the letters 'SWTW' above three downward-pointing triangles. To the right, the text reads 'IEEE SW Test Workshop' and 'Semiconductor Wafer Test Workshop'. Below this is a navigation bar with links: Home, Program, Exhibits, Corporate Support, Registration, Submissions, and Hotel.

The main content area is divided into three columns:

- Left Column:** A vertical menu with links: Home, Program, Registration, Corporate Support, Exhibits, Submissions, Hotel/Venue, Social, Committee, Industry Links, and Archive.
- Middle Column:**
 - Header: June 7 - 10, 2009 • San Diego, CA, USA
 - Section: **SWTW 2009 NOT AFFECTED BY H1N1 (SWINE FLU)**
 - Text: According to the United States Centers for Disease Control and Prevention (CDC), swine flu should not discourage people from traveling to or within the United States. Similarly, the World Health Organization continues to advise no restriction on travel related to swine flu, and no closing of borders. For continuing updates by the San Diego CVB [click here](#).
 - Text: The IEEE Semiconductor Wafer Test Workshop (SW Test Workshop) is the only IEEE Components, Packaging, Manufacturing Technology (CPMT) Society event that focuses on all the aspects associated with microelectronic wafer and die level testing. The conference has a mixture of manufacturer and vendor presentations. It is not a sales show, nor an academic or theoretical conference. It is a probe technology forum where attendees come to learn about recent developments in the industry and exchange ideas. There is a relaxed atmosphere with social activities and plenty of time for informal discussion and networking.
 - Text: The two and one half-day event starts Sunday afternoon with registration, a reception, a buffet dinner, and a panel discussion. The conference adjourns on Wednesday at noon, in time to get most participants back to work by Thursday morning. SWTW has grown to almost 500 attendees with more international visitors each year.
- Right Column:**
 - Header: Key Dates
 - Abstract Submissions: Feb. 27, 2009
 - Expo Logos: April 17, 2009
 - Corporate Support Logos: April 17, 2009
 - Corporate Support Ads: April 17, 2009
 - Online Adv. Registration: May 1, 2009
 - Corporate Support App: May 1, 2009
 - Exhibit App: April 17, 2009
 - Online Late Registration: May 15, 2009
 - Hotel Reservations: May 15, 2009
 - Final Paper Submission: May 15, 2009

Below the main content area, there is a section for '2009 Corporate Supporters' with logos for ADVANCED PROBING SYSTEMS, BucklingBeam, esi, interventional TEST SOLUTIONS, and JEM.

At the bottom of the main content area, there is a 'Key Contacts' section:

- General Chair:** Jerry Broz, Ph. D. (303) 885-1744, jerry.broz@swtest.org
- Technical Program Chair:** Brett Crump (208) 363-3745, brump@micron.com

Below this is a 'Sponsors' section.

On the far right, there is a 'Key Links' section with links to:

- SWTW Workshop Online Registration
- Corporate Support Online Registration
- Exhibitor Online Registration
- Hotel Online Reservations
- Preliminary Program (PDF)

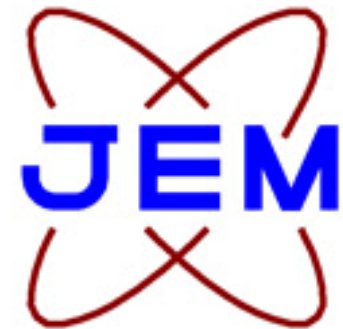


June 7 to 10, 2009

IEEE SW Test Workshop

Corporate Supporter Program

ADVANCED PROBING SYSTEMS, INC.



[®]
BucklingBeam



international
TEST SOLUTIONS



esi[®]



June 7 to 10, 2009

IEEE SW Test Workshop

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A few words about 2009

- **Overall Reduced Attendance (~65 to 70% reduction)**
 - General economic recession
 - Downturn in semiconductor and related sectors
 - Continued H1N1 swine flu warnings
- **Contracted resort minimums must be met during workshop**
 - Reserved room block
 - Food and beverages
 - IEEE / SW Test PAY the difference !

ENJOY!



We're Moving for 2010 ...



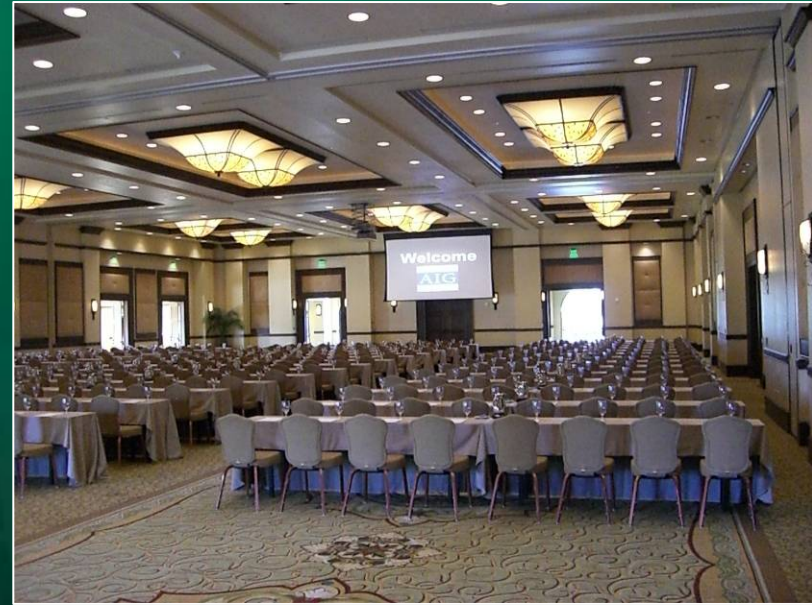
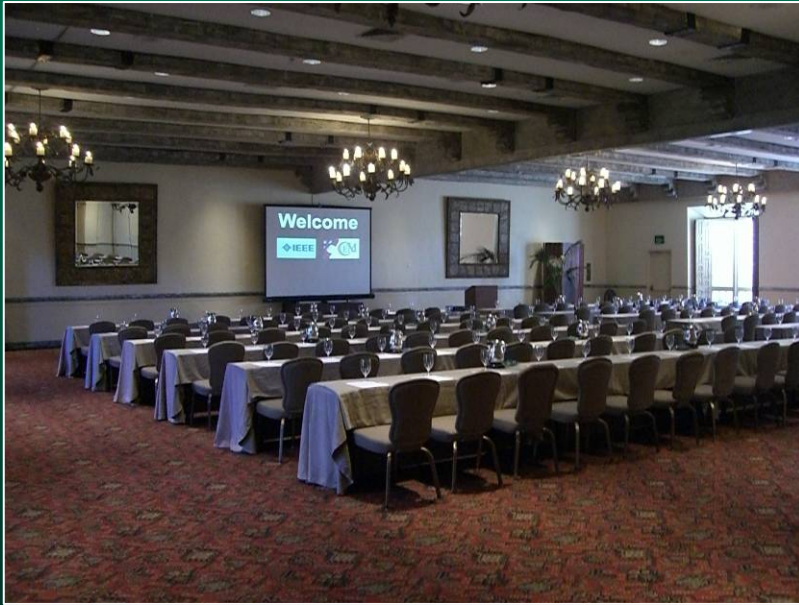
Rancho Bernardo Inn, San Diego, CA



June 7 to 10, 2009

IEEE SW Test Workshop

20th Annual SWTW 2010



June 7 to 10, 2009

IEEE SW Test Workshop

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“Who’s To Blame ... ?”

- **Organization and Technical Program ...**

- Jerry Broz, Ph.D., International Test Solutions, General Chair
- Brett Crump, Micron Technology, Program Chair
- Maddie Harwood, CEM Inc, Registration and Finance Chair
- Meredith Griffith, CEM Inc., Exhibits / Registration Coordinator

Program Committee and Steering Committee

- Ken Karklin, AeroVironment
- Patrick Mui, JEM-America
- Fred Taber, BiTS Workshop
- Darren James, Rudolph Technologies
- Warren "Stu" Crippen, Intel
- Roger Hayward, Cascade Microtech
- Jan Martens, NXP Semiconductor
- Rod Martens, Ph.D., FormFactor, Inc.
- Frank Pietzschmann, Qimonda AG
- Rey Rincon, Freescale Semiconductor



Technical Program / Agenda

- **Sunday, June 8, 2008**

- Tutorial on “Tool Metrology”
- Registration and Cocktails
- Dinner
- Probe Year In Review
- Keynote Presentation



“Economics Driving Test Technology”

Risto Pukkha

President

VLSI Research, Inc.



Technical Program / Agenda

- **Monday, June 9**

- Continental Breakfast
- Welcome and Large Array Probing
- Signal Integrity
- Lunch
- Sort Floor Data Analysis
- High Temperature Probing Challenges
- Reception / EXPO-2009 / Dinner
- Networking at Barefoot Bar or Vendor Events



Technical Program / Agenda

- **Tuesday, June 10**

- Controlling Contact Resistance
- RF Probing Challenges
- BBQ Lunch on the Paradise Lawn
- Damage Control and Low Force Probing
- EXPO-2009 in Paradise Ballroom
- Reception, Dinner, and **Casino Royal** in Sunset Ballroom !
 - Gambling, networking, prizes, FUN !



Tuesday Social

- Gambling, Prizes, FUN !
- Relaxed networking
- Dinner and Reception



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Technical Program / Agenda

- **Wednesday, June 11**
 - Continental Breakfast
 - Standards and Methods
 - Probe Potpourri
 - Awards and Adjourn Conference
 - Lunch in Bay View and Dockside Rooms



Recognition & Awards

- **Best Overall Presentation**
- **Best Data Presented**
- **Most “Inspirational” Presentation**
- **Best Presentation, Tutorial in Nature**
- **Other “Special Awards”**



SWTW-2008 Awards

Best Overall Presentation

"Methodologies for Assessing On-line Probe Process Parameters"

Jan Martens

NXP Semiconductors (Hamburg)

Simon Allgaier

FeinMetall, GmbH

Jerry Broz, Ph.D.

International Test Solutions



Best Data Presentation

"VFPP-Very Fine Pitch 60uM Probe Card Technology Optimization"

John D. Wolfe

James Tong

Norman Armendariz, Ph.D.

Texas Instruments, Inc.



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SWTW-2008 Awards

Most Inspirational Presentation

"Automatic Probe Assembly Machine"

Jung-pyo Chun
Dave Oh
Kyung-hwan Kim
TSE Co., Ltd.



Best Presentation, Tutorial in Nature

"Real-World Avalanche Testing of Single-Die, Wafers, Hybrid Modules, and Packaged Devices"

Steven T. Clauter
Integrated Technology Corporation

Taichi Ukai
Taitech



SWTW-2008 Awards

Best Poster Presentation

"Clean the WAFER, NOT the PROBE CARD!"

Terence Q. Collier

CVInc

David B. Rennie and Chuck Lhota

Air Products & Chemicals



Lifetime Achievement Award

Presented to ...

Don Snow

CEO Emeritus

Founder of Applied Precision, LLC.



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The “Special” Award



“What A Load
Of Crap !”


For the Poorest
Disguised Sales
Pitch

“What happens at SWTW stays at SWTW !”



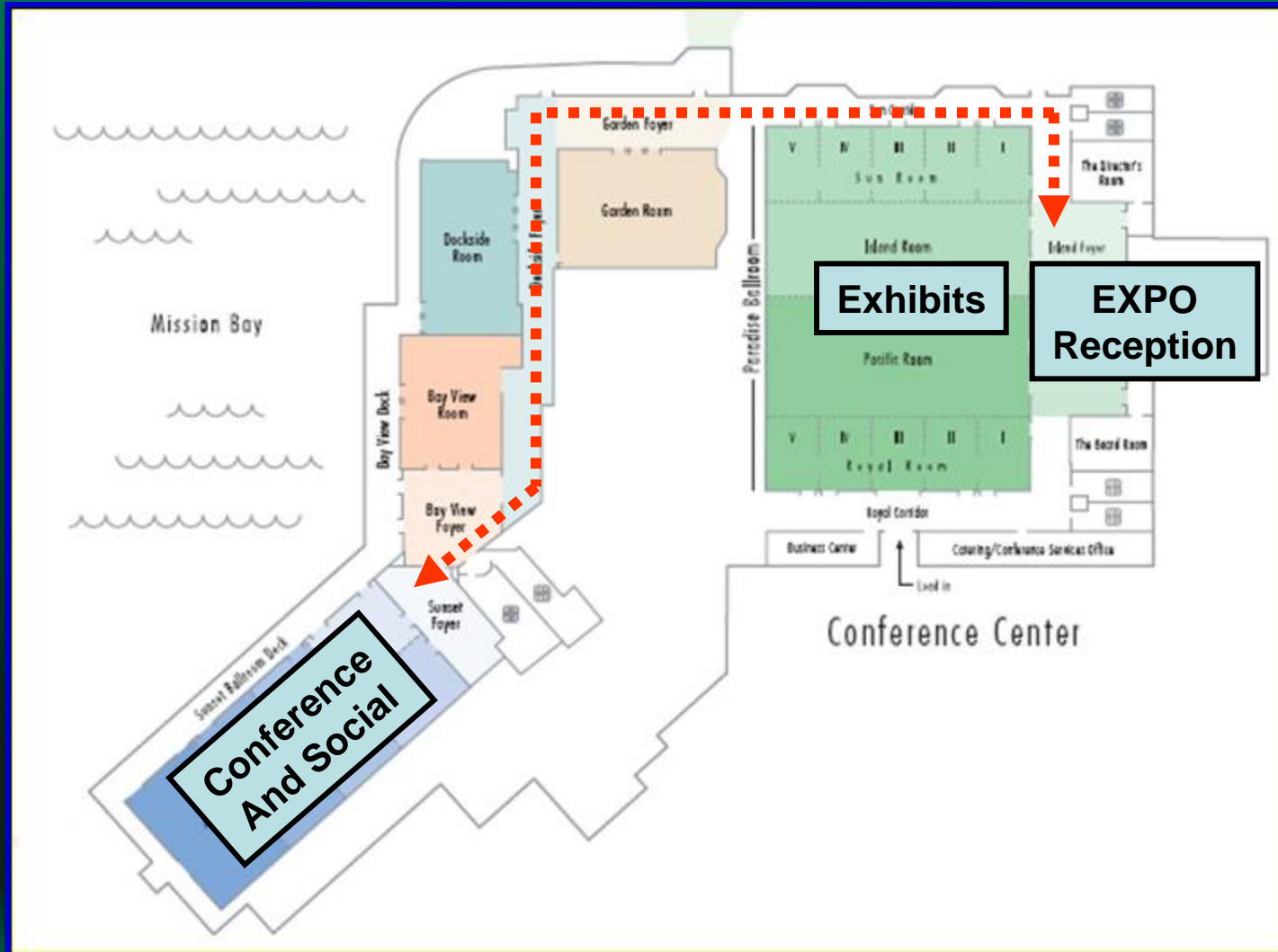
IEEE SW Test EXPO 2009

( Corporate Supporter)

- Aceris-3d Inspection, Inc.
- Acme Technology, Inc.
-  Advanced Probing Systems, Inc.
- Air Products
- Ardent Concepts, Inc.
-  BucklingBeam Solutions, LLC
-  Electro Scientific Industries, Inc. "esi"
- Elite E/M, Inc.
- ERS America
- Everett Charles Technologies
- Feinmetall GmbH
- FormFactor, Inc.
- ICOS Vision Systems / KLA-Tencor
- Integrated Test Corporation
- Interconnect Devices, Inc.
-  International Test Solutions, Inc.
-  JEM America Corp.
- Left Coast Instruments
- MicroProbe
- NHK Spring Co., Ltd
- Probe Logic
- Rudolph Technologies, Inc.
- Spire Manufacturing
- SUSS MicroTec
- SV Probe, Inc. - An Ellipsiz Company
- T.I.P.S. Messtechnik GmbH
- Taconic
- Technoprobe, America
- Tokyo Electron Limited
- Vermont Mold & Tool
- Wentworth Laboratories, Inc.



Don't Get Lost !



Don't Get Lost in Paradise !



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Mesa, Arizona



- IS-Test Workshop
Freising, Germany



- Electronic Components and Technology Conference
San Diego, CA



Silence your cell phone !!!

